

Erratum: “Highly accelerated lifetime testing of potassium sodium niobate thin films” [Appl. Phys. Lett. 111, 212903 (2017)]

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We have noticed that there are typographical errors in the voltage acceleration factors in the originally published article¹. Corrected values are given below.

In the abstract and conclusions (first paragraph of left column in Page 4), the correct voltage acceleration factor ($N_{3\mu\text{m}}$) for the 3 μm thick film is -4.14 ± 0.27 . The voltage acceleration factors for the 2 μm thick film are -6.75 ± 0.87 ($N_{2\mu\text{m}1}$) and -6.91 ± 0.33 ($N_{2\mu\text{m}2}$), respectively. The small changes in voltage acceleration factors (for the 3 μm thick film, $N_{3\mu\text{m}}$ changed from -3.5 ± 0.34 to -4.14 ± 0.27 ; for the 2 μm thick film, $N_{2\mu\text{m}1}$ and $N_{2\mu\text{m}2}$ changed from -6.67 and -6.94 ± 0.23 to -6.75 ± 0.87 and -6.91 ± 0.33 , respectively) were caused by the addition of new data points in the linear fitting for the electrical field dependence of the medium time to failure (t_{50}).

One page 3 (related to FIG. 4), in the second paragraph of the left column, “ $N_{a2\mu1}$ ”, “ $N_{a2\mu2}$ ”, and “ $N_{a3\mu}$ ” should be replaced by “ $N_{2\mu\text{m}1}$ ”, “ $N_{2\mu\text{m}2}$ ” and “ $N_{3\mu\text{m}}$ ”. One page 4, in the first paragraph of the left column, “ $N_{3\mu}$ ”, “ $N_{a2\mu1}$ ”, and “ $N_{a2\mu3}$ ” should be replaced by “ $N_{3\mu\text{m}}$ ”, “ $N_{2\mu\text{m}1}$ ” and “ $N_{2\mu\text{m}2}$ ”.

[The caption of Fig. 4 has also been corrected.](#)

However, all of the results presented in the published article remain the same, the results and conclusion of the article are not affected by the errors. We apologize to the readers of Applied Physics Letters for any confusion that might have been caused.

1 W. Zhu, B. Akkopru-Akgun, S. Troler-McKinstry, Appl. Phys. Lett. 111212903 (2017).